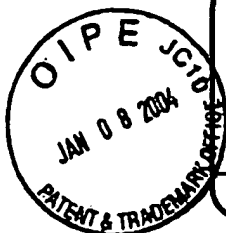


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Sheet **2** of **6**

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Application Number	10/600,224
Filing Date	6/20/2003
First Named Inventor	Bickford, Randall L.
Group Art Unit	2121
Examiner Name	Not yet Assigned
Attorney Docket Number	23404-cpa

U.S. PATENT DOCUMENTS

Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
RF	21	5,706,321		Chen et al.	06-06-1998	
	22	5,740,033		Wassick et al.	04-14-1998	
	23	5,745,382		Vilim et al.	04-28-1998	
	24	5,761,090		Gross et al.	06-02-1998	
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	34	6,073,262		Larkin, et al.	06-06-2000	

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Examiner Initials ¹	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Ts
		Office ³	Number ⁴	Kind Code ⁵ (if known)				

Examiner Signature <i>Ramesh Patel</i>	Date Considered <i>10/26/04</i>
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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Sheet 3

of 6

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Application Number

Filing Date

First Named Inventor Bickford, Randall L.

Group Art Unit

Examiner Name

Attorney Docket Number 23404-cpa

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
<i>RL</i>	35	BICKFORD, R.L., Phase Partitioning the Multivariate State Estimation Technique (MSET) Process for Improved Parameter Estimation Performance and Processing Speed, New Technology Report, January 13, 2000, Printed in USA by Expert Microsystems, Inc.	
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Sheet 4

of 6

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Application Number

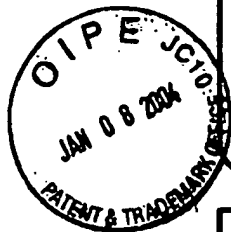
Filing Date

First Named Inventor Bickford, Randall L.

Group Art Unit

Examiner Name

Attorney Docket Number 23404-cpa



OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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Sheet 5 of 6

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Application Number	
Filing Date	
First Named Inventor	Bickford, Randall L.
Group Art Unit	
Examiner Name	
Attorney Docket Number	23404-cpa

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner Initials ¹	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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10/26/04

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Complete if Known**Application Number****Filing Date**

First Named Inventor	Bickford, Randall L.
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Group Art Unit

Examiner Name

Attorney Docket Number	23404-cpa
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(use as many sheets as necessary)

Sheet	6	of	6
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[illegible]

**Examiner
Signature**

Ramesh Patel

Date Considered

10/26/04

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